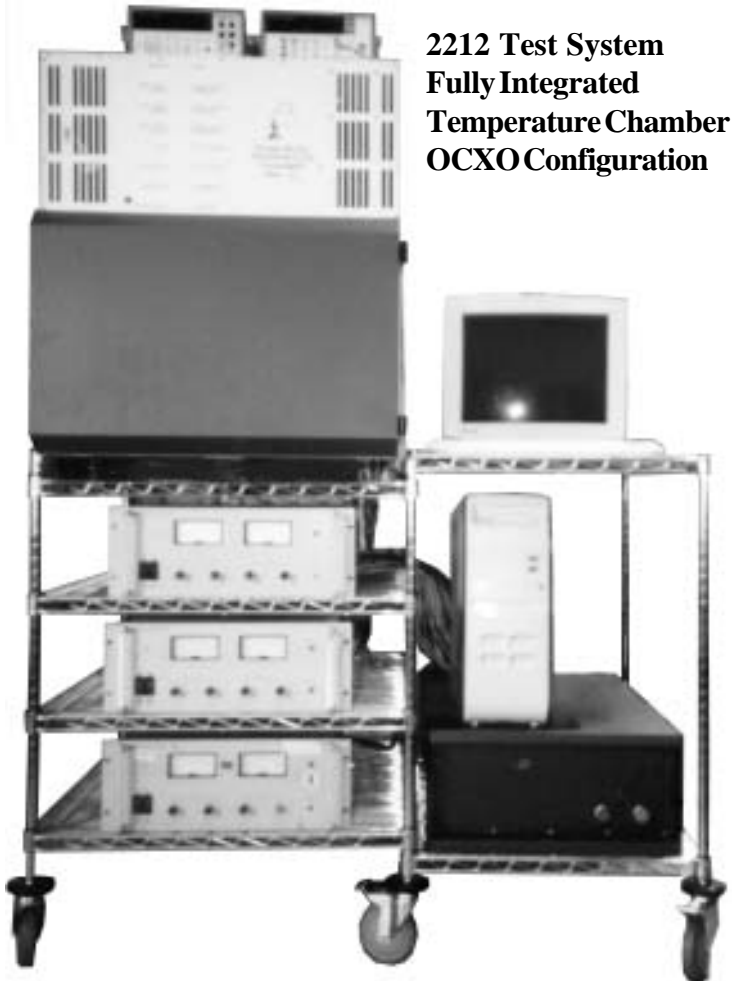
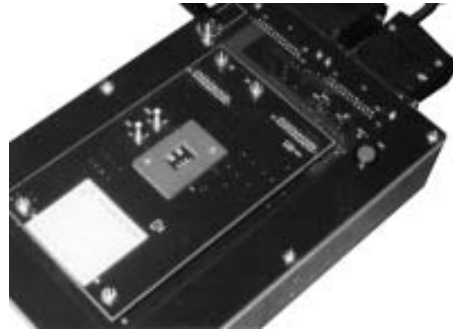


Test, Measurement and Process Control



**2212 Test System
Fully Integrated
Temperature Chamber
OCXO Configuration**



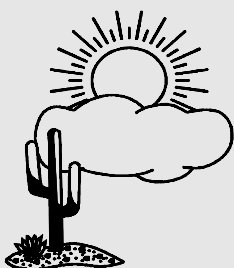
**SMD Bench
Test Fixtures
ECL-PECL
Dual Output
4GHz BW**

2212 Test Card for Large Leaded Parts



Test Systems for:

- **TTL/CMOS/ECL/PECL/LVDS/Sinewave**
- **VCXO/TCXO/VCTCXO/OCXO/clocks**
- **SMD and Leaded parts**
- **5x7, 5x3.2, 4x2 and other SMD parts**
- **Supply voltages from 1.2V to 27V**
- **ASIC TCXO compensation capabilities**
- **Thermistor TCXO compensation**
- **Up to 1200 devices per temperature run.**
- **Measure: Waveform, jitter, frequency**
- **Oscillator Start Time**
- **Bandwidths to over 4GHz**
- **OCXO Warm-up Characterization**
- **Multi OCXO bench top test system**
- **180 OCXOs/run up to 350A power**
- **Aging measurements - crystals**
- **Aging measurements - oscillators**
- **Fast Crystal Perturbation screening**
- **Test chambers with excellent uniformity**
- **Room temperature testing and fixtures**
- **Handler sorting systems**
- **Network compatible software**
- **Data directly to a spreadsheet option**



PRA Inc.

4821 226th Place NE

Arlington, Washington 98223 U.S.A.

TEL:425-673-6061

FAX:425-673-6087

e-mail:sales@prainctest.com

www.prainctest.com